

1. Scope

This specification applies to KNTC0201/10KF3380 of chip NTC thermistors.

Shape and Dimensions 2.

- 1) Dimensions: See Fig.2-1 and Table 2-1.
- 2) Recommended PCB pattern for reflow soldering: See Fig.2-2 and Table 2-1.





	Fig. 2-1		[Table 2-1]			Unit: mm [inch]	
Туре	L	w	т	а	A	В	С
0603	0.6±0.05	0.3±0.05	0.3±0.05	0.15±0.05	0.20 - 0.20	0.20 ~ 0.20	20~0.30 0.30~0.35
[0201]	[0.024±0.002]	[0.012±0.002]	[0.012±0.002]	[0.006±0.002]	0.20/~0.30	0.20/~0.30	

Electrical Characteristics 3.

Part Number	Resistance at 25℃ R25 (kΩ)	B constant (25-50℃) (K)	Max. Permissive Operating Current (25℃) (mA)	Thermal Time Constant	Dissipation Factor (mW/℃)	Rated Electric Power (mW)
KNTC0201/10KF3380	10	3380	0.31	<3sec	1.0	100

Operating and storage temperature range (individual chip without packing): -55 $^\circ\!\!\mathbb{C}$ ~ +125 $^\circ\!\!\mathbb{C}$ 1)

2) Storage temperature range (packing conditions): -10 $^\circ\!\mathrm{C}$ +40 $^\circ\!\mathrm{C}$ and RH 75% (Max.)



TYPICAL ELECTRICAL CHARACTERISTICS



4. Test and Measurement Procedures

4.1 Test Conditions

4.1.1 Unless otherwise specified, the standard atmospheric conditions for measurement/test as:

- a. Ambient Temperature: 20±15°C
- b. Relative Humidity : 65±20%
- c. Air Pressure: 86kPa to 106kPa
- 4.1.2 If any doubt on the results, measurements/tests should be made within the following limits:
 - a. Ambient Temperature: 20±2°C
 - b. Relative Humidity: 65±5%
 - c. Air Pressure: 86kPa to 106kPa

4.2 Visual Examination

a. Inspection Equipment: $20 \times$ magnifier



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Items	Requirements	Test Methods and Remarks
4.3.1 Nominal	Refer to Item 4	Ambient temperature: 25±0.2°C. Measuring electric power: 0.1mW Max.
Zero-Power		······································
Resistance (R25)		
4.3.2	Refer to Item 4	Measure the resistance at the ambient temperature of $25{\pm}0.2^\circ\!\mathrm{C}$
Nominal B		and 50±0.2℃
Constant		InP25-InP50
		$B = \frac{1/T_{25} - 1/T_{50}}{1/T_{25} - 1/T_{50}}$
		T: absolute temperature (K)
4.3.3	Refer to Item 4	The total time for the temperature of the thermistor to change by
Constant	│ ↑	b3.2% of the difference from ambient temperature $I_0(C)$ to $I_1(C)$ by the drastic change of the power applied to thermistor from
(single unit)	T ₁	Non-zero Power to Zero-Power state.
	To Time	
4.3.4 Dissipation	Refer to Item 4	The total electric power required to raise the temperature of the
Constant (single unit)		element by 1° through self-heating under thermal equilibrium. It calculates by next formula.
		$C = \frac{W}{T - T_0}$
4.3.5 Rated Power	Refer to Item 4	The necessary electric power makes thermistor's temperature rise 100° by self-heating at ambient temperature 25° .
4.3.6 Permissive operating current	Refer to Item 4	The current that keeps body temperature of chip NTC on the PC board in still air rising 1°C by self-heating.



KNTC0201/10KF3380

4.4 Reliability Test

Items	Requirements	Test Methods and Remarks		
4.4.1. Terminal Strength	No removal or split of the termination or other defects shall occur. Chip F Mounting Pad Glass Epoxy Board Fig.4.4.1-1	 Solder the chip to the testing jig (glass epoxy board shown in the following Fig. 4.4.1-1) using eutectic solder. Then apply a force in the direction of the arrow. 2N force for 0603 series, Keep time: 10±1s. 		
4.4.2 Resistance to Flexure	No visible mechanical damage. Unit: mm [inch] Type a b c 0603[0201] 0.25 0.8 0.3 0603[0201] 0.25 0.8 0.3 0603[0201] 0.25 0.8 0.3	 Solder the chip to the test jig (glass epoxy board shown in Fig. 4.4.2-1) using a eutectic solder. Then apply a force in the direction shown in Fig. 4.4.2-2. Flexure: 2mm. Pressurizing Speed: 0.5mm/sec. Keep time: 30 sec. 		
4.4.3 Vibration	No visible mechanical damage. Cu pad Solder mask Glass Epoxy Board Fig. 4.4.3-1	 Solder the chip to the testing jig (glass epoxy board shown in Fig. 4.4.3-1) using eutectic solder. The chip shall be subjected to a simple harmonic motion having total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55 Hz. The frequency ranging from 10 to 55 Hz and returning to 10 Hz shall be traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3 mutually perpendicular directions (total of 6 hours). 		
4.4.4 Dropping	No visible mechanical damage.	Drop chip inductor 10 times on a concrete floor from a height of 100 cm.		
4.4.5 Solderability	 No visible mechanical damage. Wetting shall exceed 80% coverage. 	 Solder temperature: 240±2°C. Duration: 3 sec. Solder: Sn/3.0Ag/0.5Cu. Flux: 25% Resin and 75% ethanol in weight. 		
4.4.6 Resistance to Soldering Heat	 No visible mechanical damage. R25 change: within ±1%. B Constant change: within ±1%. 	 Solder temperature: 260±3℃ Duration: 5 sec. Solder: Sn/3.0Ag/0.5Cu. Flux: 25% Resin and 75% ethanol in weight. The chip shall be stabilized at normal condition for 1~2 hours before measuring. 		



4.4.7	 No visible mechanical damage. 	1) Temperature, Time: -55 $^{\circ}$ C for 30±3 min \rightarrow 125 $^{\circ}$ C for 30±3min.
Thermal Shock	 R25 change: within ±1%. 	② Transforming interval: 20sec. Max.
	③ B Constant change: within ±1%.	③ Tested cycle: 100 cycles.
		④ The chip shall be stabilized at normal condition for 1~2 hours
		before measuring.
	125℃ 30 min. 30 min.	
	Ambient	
	Iemperature	
	Fig. 4.4.7-1	
	-	
4.4.8	1 No visible mechanical damage.	① Temperature: -55±2℃
Resistance to	② R25 change: within ±1%.	2 Duration: 1000^{+24} hours.
Low	③ B Constant change: within ±1%.	③ The chip shall be stabilized at normal condition for 1~2 hours
Temperature		before measuring.
449	1 No visible mechanical damage	① Temperature: 125+2℃
Resistance	 R25 change: within +1% 	
to High	$ = \frac{1}{1000} = $	2 The chin shall be stabilized at normal condition for 1, 2 hours
Tomporatura	∃ B Constant change. within ±1 /8.	before measuring
remperature		belore measuring.
4.4.10	① No visible mechanical damage.	① Temperature: 60±2℃
Damp Heat	② R25 change: within ±1%.	② Humidity: 90% to 95% RH.
(Steady States)	③ B Constant change: within ±1%.	③ Duration: 1000 ⁺²⁴ hours.
		(\P) The chip shall be stabilized at normal condition for 1~2 hours
		before measuring.
4.4.11	① No visible mechanical damage.	① Temperature: 85±2℃
Loading at High	② R25 change: Within ±1%.	② Duration: 1000 ⁺²⁴ hours.
Temperature	③ B constant change: Within ±1%.	③ Applied current: Max. Permissive Operating Current.
(Life Test)		4 The chip shall be stabilized at normal condition for 1~2 hours
		before measuring.

5. Recommended Soldering Technologies

- 5.1 Re-flowing Profile:
- \triangle Preheat condition: 150 ~200°C/60~120sec.
- \triangle Allowed time above 217°C: 60~90sec.
- △ Max temp: 260°C
- \bigtriangleup $\;$ Max time at max temp: 10sec.
- ∧ Solder paste: Sn/3.0Aa/0.5Cu

[Note: The reflow profile in the above table is only for qualification and is not meant to specify board assembly profiles. Actual board assembly profiles must be based on the customer's specific board design, solder paste and process, and should not exceed the parameters as the Reflow profile shows.]





- \bigtriangleup ~ Iron soldering power: Max.30W
- \triangle Pre-heating: 150 °C / 60 sec.
- \triangle Soldering Tip temperature: 350°C Max.
- \triangle Soldering time: 3 sec Max.
- △ Solder paste: Sn/3.0Ag/0.5Cu
- \triangle Max.1 times for iron soldering

[Note: Take care not to apply the tip of the soldering iron to the terminal electrodes.]

单击下面可查看定价,库存,交付和生命周期等信息

>>KUU(永裕泰)